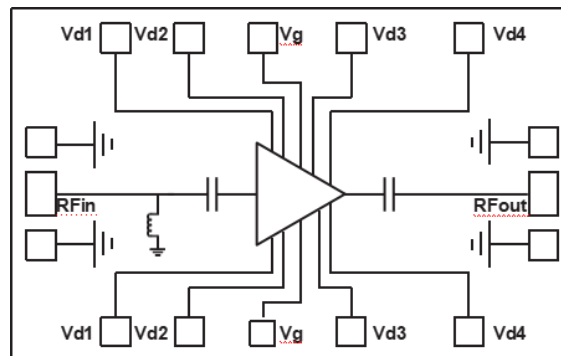


**Features**

- Frequency: 32-35GHz
- Gain: 23dB
- Psat:+ 33dBm
- Power Supply : +6.0V@1000mA
- Die Size : 3.25 x 1.8 mm

**Typical Applications**

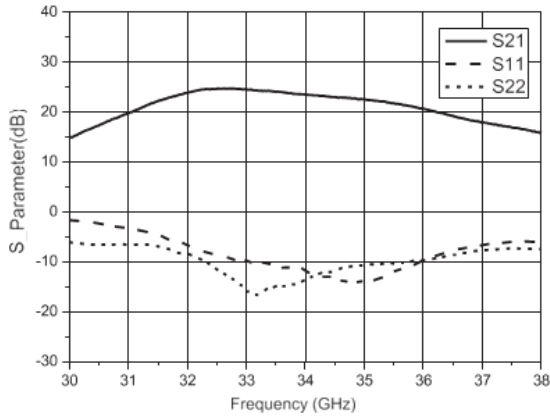
- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

**Functional Block Diagram**

**Electrical Specifications**
**TA = +25°C, Vdd = +6V, Vgg = -0.35V (On-wafer Measurement Results)**

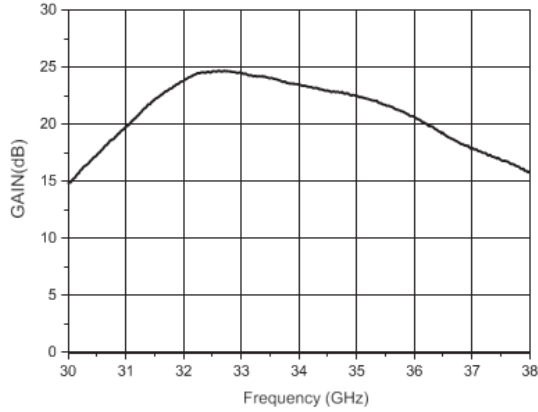
Parameters	Min.	Typ.	Max.	Units
<b>Frequency</b>		<b>32-35</b>		<b>GHz</b>
<b>Gain</b>		<b>23</b>		<b>dB</b>
<b>Psat</b>		<b>33</b>		<b>dBm</b>
<b>Input Return Loss</b>		<b>11</b>		<b>dB</b>
<b>Output Return Loss</b>		<b>13</b>		<b>dB</b>
<b>Operating Current</b>		<b>1000</b>		<b>mA</b>



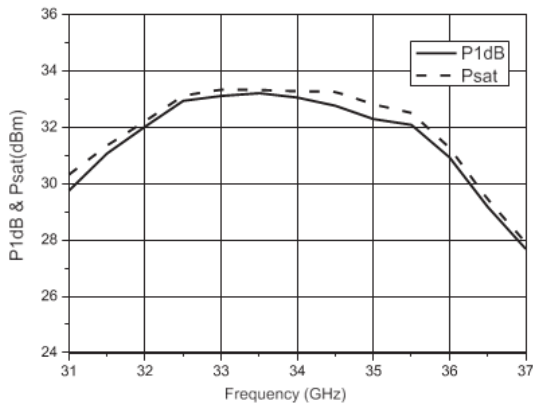
### S Parameter vs. Frequency



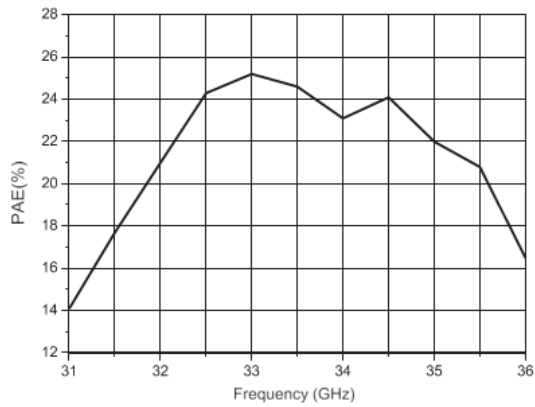
### Gain vs. Frequency



### P1dB & Psat vs. Frequency

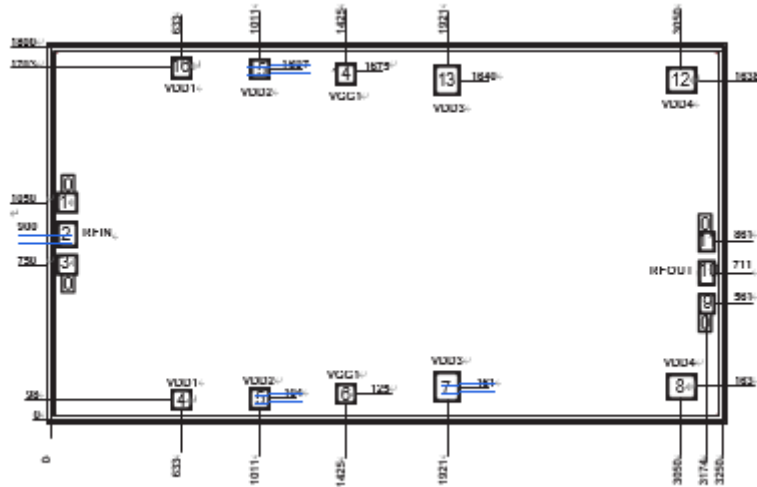


### PAE vs. Frequency





### Outline Drawing: All Dimensions in $\mu\text{m}$

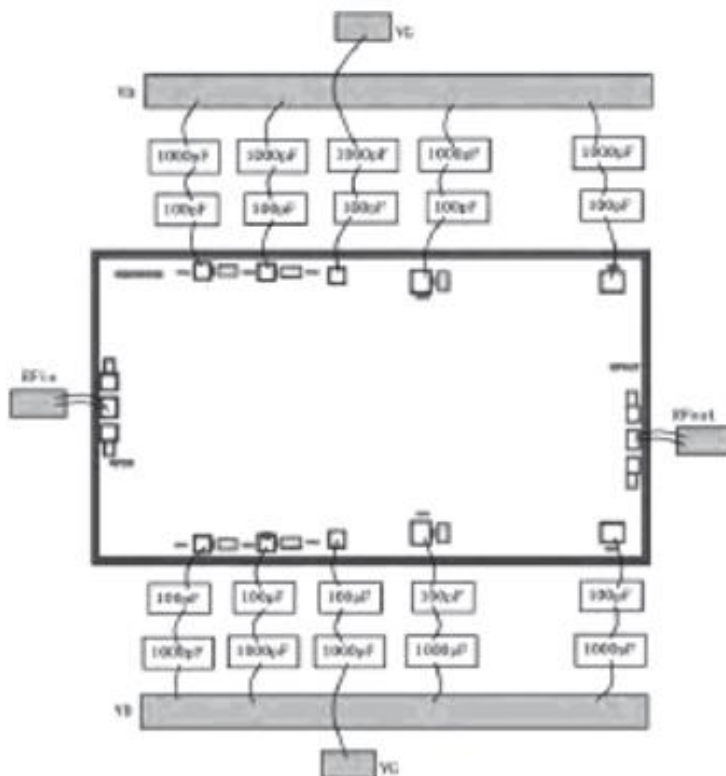


### Pad Description

Pad	Function	Description
2	RF IN	Signal input terminal, connected to 50 $\Omega$ circuit.
10	RF OUT&VDD	Signal output terminal, connected to 50 $\Omega$ circuit.
4,5,7,8,12,13,15,16	Vdd	Amplifier power supply, external 100pF capacitor required.
6,14	Vgg	Amplifier gate power supply, external 100pF capacitor required.
1,3,9,11	GND	Die bottom must be connected to RF/DC ground.



### Assembly Drawing (Bond testing)



#### Notes:

1. Die thickness: 100um
2. Typical bond pad is 100\*100  $\mu\text{m}^2$
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

#### Maximum Ratings:

1. Supply voltage: +7V
2. RF Input power: +5dBm
3. Operating temperature: -55°C to +85°C
4. Storage temperature: -65°C to +150°C